



FDP2710_F085

N-Channel PowerTrench® MOSFET

250V, 50A, 47mΩ

Features

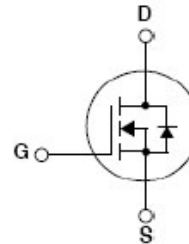
- Typ $r_{DS(on)}$ = 38mΩ at $V_{GS} = 10V$, $I_D = 50A$
- Typ $Q_{g(TOT)}$ = 78nC at $V_{GS} = 10V$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low $R_{DS(on)}$
- High power and current handling capability
- Qualified to AEC Q101
- RoHS Compliant

General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Applications

- PDP application
- Hybrid Electric Vehicle DC/DC converters



MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Ratings | Units |
|----------------|---|--------------|---------------------------|
| V_{DSS} | Drain to Source Voltage | 250 | V |
| V_{GS} | Gate to Source Voltage | ± 30 | V |
| I_D | Drain Current Continuous ($T_C < 50^\circ\text{C}$, $V_{GS} = 10\text{V}$) | 50 | A |
| | Continuous ($T_{amb} = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$, with $R_{\theta JA} = 62^\circ\text{C/W}$) | 4 | |
| | Pulsed | See Figure 4 | |
| E_{AS} | Single Pulse Avalanche Energy (Note 1) | 483 | mJ |
| P_D | Power Dissipation | 403 | W |
| | Derate above 25°C | 3.2 | $\text{W}/^\circ\text{C}$ |
| T_J, T_{STG} | Operating and Storage Temperature | -55 to +150 | $^\circ\text{C}$ |

Thermal Characteristics

| | | | |
|-----------------|---|------|--------------------|
| $R_{\theta JC}$ | Maximum Thermal Resistance Junction to Case | 0.31 | $^\circ\text{C/W}$ |
| $R_{\theta JA}$ | Maximum Thermal Resistance Junction to Ambient (Note 2) | 62 | $^\circ\text{C/W}$ |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|--------------|---------|-----------|------------|----------|
| FDP2710 | FDP2710_F085 | TO220 | Tube | NA | 50 units |

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

Off Characteristics

| | | | | | | |
|--------------------------------|---|--|-----|------|-----------|---------------------------|
| B_{VDSS} | Drain to Source Breakdown Voltage | $I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$ | 250 | - | - | V |
| $\Delta BV_{DSS} / \Delta T_J$ | Breakdown Voltage Temperature Coefficient | $I_D = 250\mu\text{A}$, Referenced to 25°C | - | 0.25 | - | $\text{V}/^\circ\text{C}$ |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 250\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 125^\circ\text{C}$ | - | - | 1 | μA |
| I_{GSS} | Gate to Source Leakage Current | $V_{GS} = \pm 30\text{V}$ | - | - | ± 100 | nA |

On Characteristics

| | | | | | | |
|--------------|----------------------------------|---|---|-----|-----|------------|
| $V_{GS(th)}$ | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$ | 3 | 3.9 | 5 | V |
| $r_{DS(on)}$ | Drain to Source On Resistance | $I_D = 50\text{A}$, $V_{GS} = 10\text{V}$, | - | 38 | 47 | m Ω |
| | | $I_D = 50\text{A}$, $V_{GS} = 10\text{V}$, $T_J = 150^\circ\text{C}$ | - | 104 | 129 | |
| g_{FS} | Forward Transconductance | $I_D = 25\text{A}$, $V_{DS} = 10\text{V}$ | - | 63 | - | S |

Dynamic Characteristics

| | | | | | | |
|--------------|-------------------------------|--|---|------|-----|----|
| C_{iss} | Input Capacitance | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$ | - | 5690 | - | pF |
| C_{oss} | Output Capacitance | | - | 425 | - | pF |
| C_{rss} | Reverse Transfer Capacitance | | - | 115 | - | pF |
| $Q_{g(TOT)}$ | Total Gate Charge at 20V | $V_{GS} = 0$ to 10V $V_{DD} = 125\text{V}$ $I_D = 50\text{A}$ | - | 78 | 101 | nC |
| Q_{gs} | Gate to Source Gate Charge | | - | 31 | - | nC |
| Q_{gd} | Gate to Drain "Miller" Charge | | - | 20 | - | nC |

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

Switching Characteristics

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------------|---------------------|---|-----|-----|-----|-------|
| $t_{d(on)}$ | Turn-On Delay Time | $V_{DD} = 125\text{V}, I_D = 50\text{A}$ $V_{GS} = 10\text{V}, R_{GEN} = 25\Omega$ | - | 85 | - | ns |
| t_r | Rise Time | | - | 183 | - | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | | - | 140 | - | ns |
| t_f | Fall Time | | - | 121 | - | ns |

Drain-Source Diode Characteristics

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|----------|---|---|-----|-----|-----|---------------|
| I_S | Maximum Continuous Drain-Source Diode Forward Current | | - | - | 50 | A |
| I_{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | - | - | 150 | A |
| V_{SD} | Source to Drain Diode Voltage | $I_{SD} = 50\text{A}$ | - | 0.9 | 1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_{SD} = 50\text{A}, dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | 166 | 216 | ns |
| Q_{rr} | Reverse Recovery Charge | | - | 1 | 1.3 | μC |

Notes:

- 1: Starting $T_J = 25^\circ\text{C}$, $L = 1.68\text{mH}$, $I_{AS} = 24\text{A}$.
- 2: Pulse width 100s

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: <http://www.aecouncil.com/>
 All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Typical Characteristics

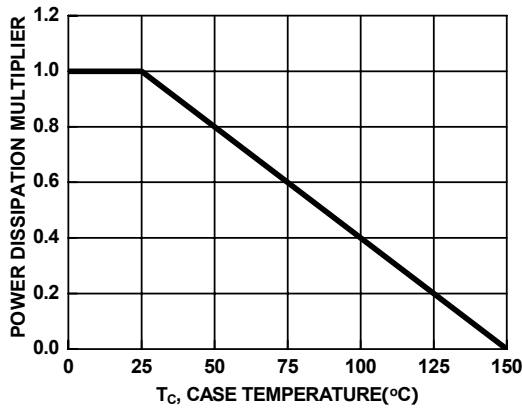


Figure 1. Normalized Power Dissipation vs Case Temperature

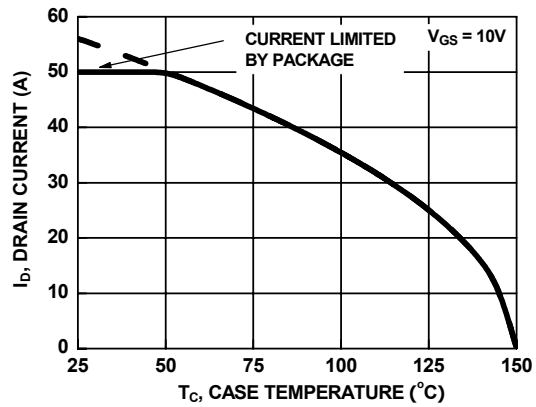


Figure 2. Maximum Continuous Drain Current vs Case Temperature

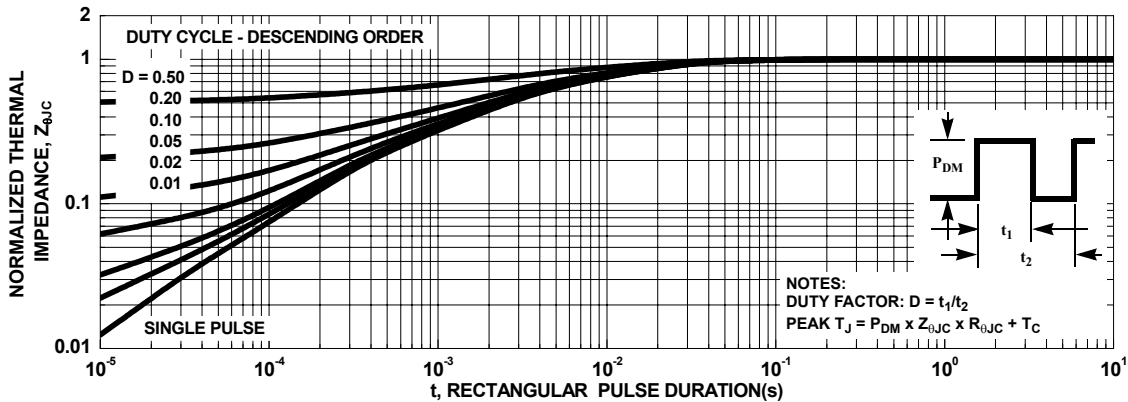


Figure 3. Normalized Maximum Transient Thermal Impedance

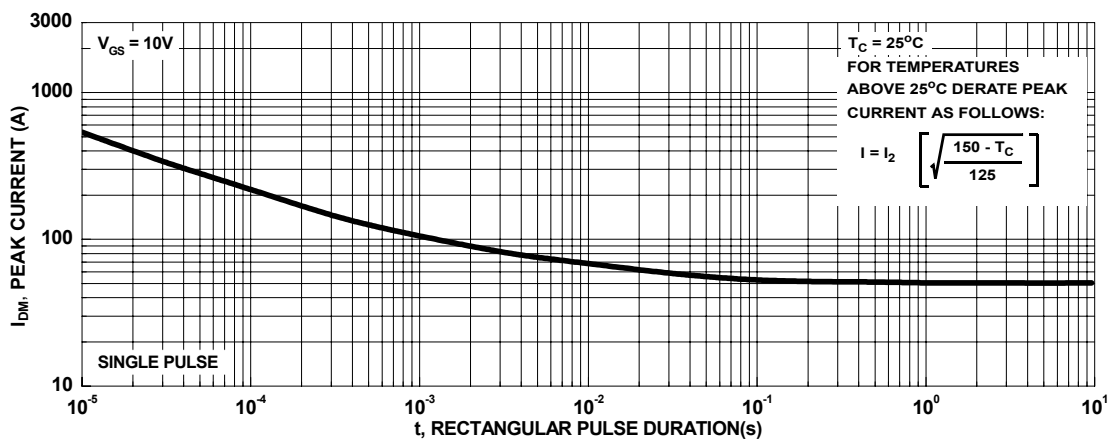


Figure 4. Peak Current Capability

Typical Characteristics

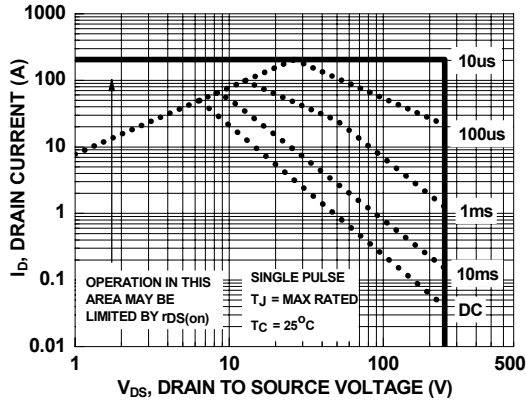
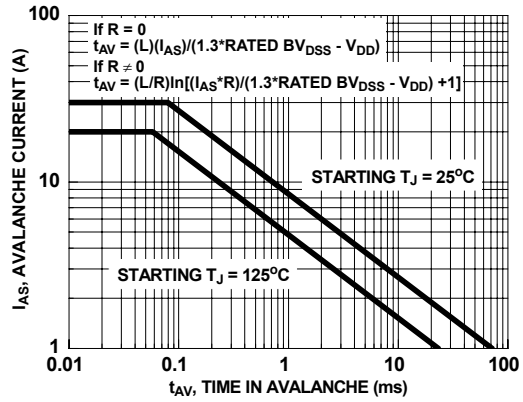


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

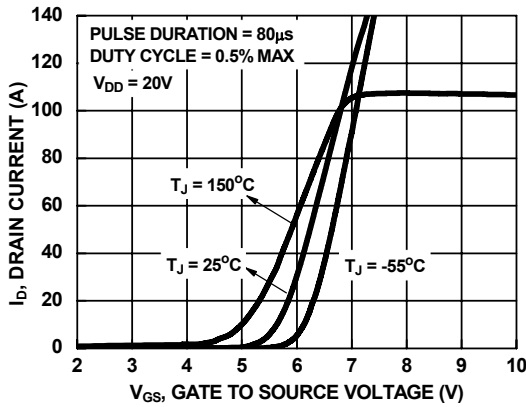


Figure 7. Transfer Characteristics

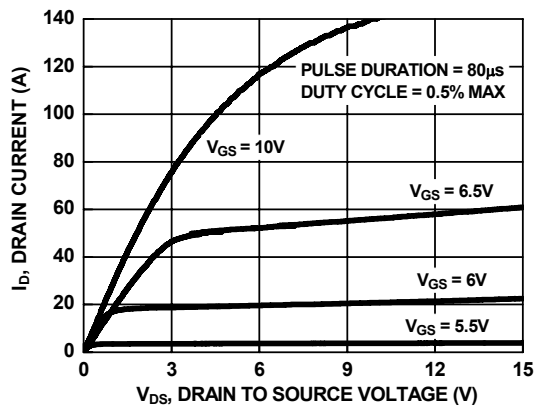


Figure 8. Saturation Characteristics

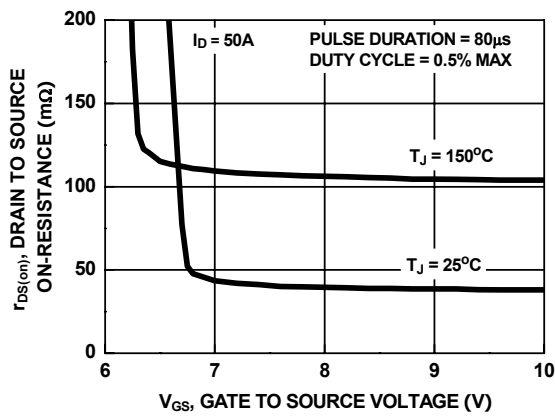


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

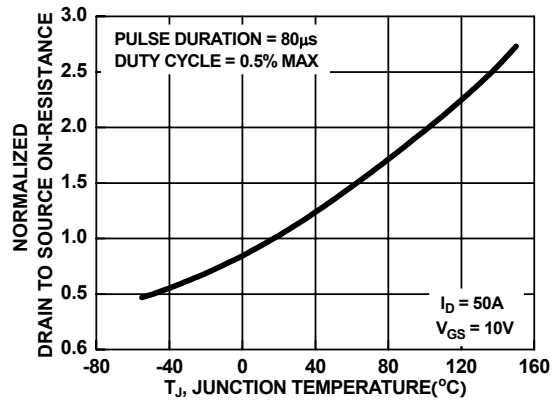


Figure 10. Normalized Drain to Source On-Resistance vs Junction Temperature

Typical Characteristics

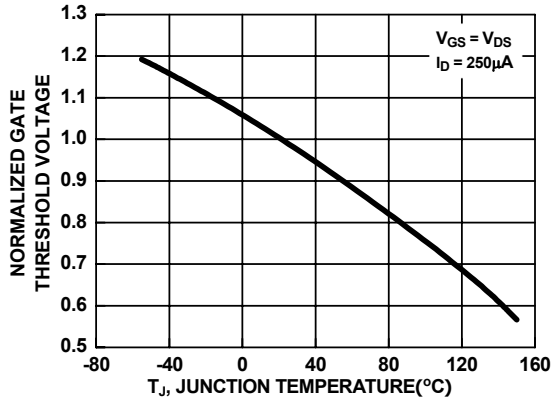


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

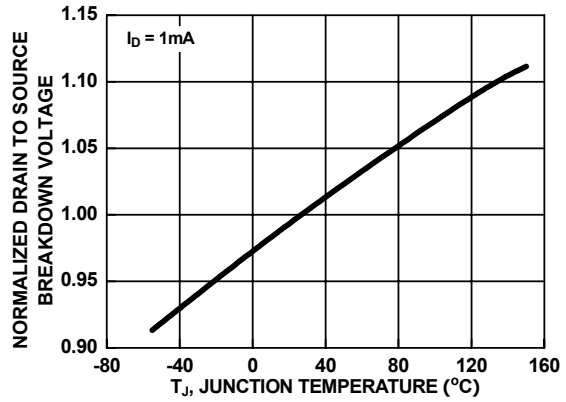


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

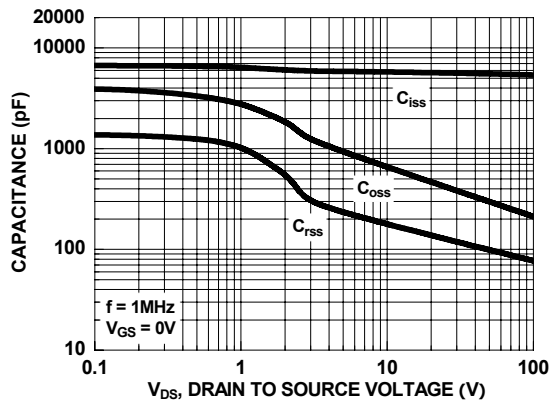


Figure 13. Capacitance vs Drain to Source Voltage

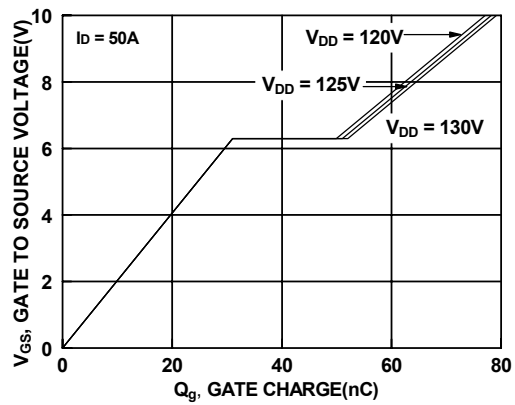



Figure 14. Gate Charge vs Gate to Source Voltage



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